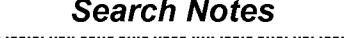
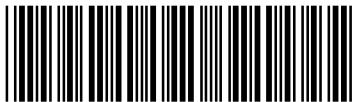


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/623,761	LARAGH, JOHN H.	
	Examiner	Art Unit	
	BIN SHEN	1657	

Search Notes



Application/Control No.

10/623,761

Examiner

BIN SHEN

**Applicant(s)/Patent under
Reexamination**

LARAGH, JOHN H.

Art Unit

1657

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)